I. CLAIM AMENDMENTS

CLAIMS:

- 1. (Currently Amended) A particle detection unit that detects secondary electrons along an electron flight path, comprising:
 - a detector for detecting the electrons; and
- a suppression grid placed in the electron flight path in front of the detector, the grid being made from a conductive material such that it may receive an applied voltage and the grid operable to transmit to the detector only a fraction of the electrons received at the grid actively repel a portion of the electrons, such that they do not reach the detector through the grid, with the portion of repelled electrons being determined by the amount of applied voltage.
- 2. (Original) The detection unit of Claim 1, further comprising control electronics for varying the voltage applied to the suppression grid.
- 3. (Original) The detection unit of Claim 1, wherein the detector is a microchannel plate.
- 4. (Original) The detection unit of Claim 1, further comprising a calibration unit programmed to perform calibration programmed to varied to voltage applied to the suppression unit.
- 5. (Original) The detection unit of Claim 1, further comprising a secondary electron emission surface for scattering electrons to be received at the suppression grid.
- 6. (Original) The detection unit of Claim 5, wherein the secondary election emission surface is a foil.
 - 7. (Currently Amended) A method of counting particles, comprising the steps of: producing secondary electrons at a secondary electron emission surface;

receiving the secondary electrons at a detector;

placing a suppression grid in the electron flight path in front of the detector, the grid being made from a conductive material; and

applying a voltage to the grid such that the grid is operable to transmit to the detector only a fraction of the electrons received at the grid actively repel a portion of the electrons, such that they do not reach the detector through the grid, with the portion of repelled electrons being determined by the amount of applied voltage.

- 8. (Original) The method of Claim 7, further comprising the step of setting the applied voltage to receive a known percentage of the electrons.
- 9. (Original) The method of Claim 7, further comprising the step of periodically scanning a range of voltages applied to the suppression grid.
- 10. (Original) The method of Claim 9, further comprising the steps of storing data representing a count of the electrons received at the grid as a function of voltage applied to the grid and of comparing measured data to the stored data.
- 11. (Original) The method of Claim 9, further comprising the steps of measuring counts of the electrons received at the grid as a function of their energy, and of comparing the measured data to stored calibration data.
- 12. (Original) The method of Claim 9, further comprising the step of measuring counts of the electrons received at the grid as a function of their species, and of comparing the measured data to stored calibration data.
- 13. (Original) The method of Claim 9, wherein the steps are repeated at a second detector.
- 14. (Original) The method of Claim 13, further comprising the steps of using measured data from two detectors for calibration purposes.

- 15. (Currently Amended) A time-of-flight mass spectrometer that receives particles, comprising:
- a foil for transmitting the particles and producing secondary electrons from the particles at the output side of the foil;
 - a start detector for counting electrons generated from the foil;
 - a stop detector for counting particles transmitted through the foil; and

for at least one of the detectors, a suppression grid placed in the particle flight path in front of the detector, the grid being made from a conductive material such that it may receive an applied voltage and the grid operable to transmit to the detector only a percentage of the particles received at the suppression grid actively repel a portion of the electrons, such that they do not reach the detector through the grid, with the portion of repelled electrons being determined by the amount of applied voltage.

- 16. (Original) The spectrometer of Claim 15, wherein the suppression grid is in front of the start detector.
- 17. (Original) The spectrometer of Claim 15, wherein the suppression grid is in front of the stop detector.
- 18. (Original) The spectrometer of Claim 15, further comprising control electronics for varying the voltage applied to the suppression grid.
- 19. (Currently Amended) The spectrometer of Claim 15, wherein the at least one of the start detector or stop detector is a microchannel plate.
- 20. (Original) The spectrometer of Claim 15, further comprising a calibration unit programmed to perform calibration programmed to varied to voltage applied to the suppression unit.
- 21. (Original) The spectrometer of Claim 15, further comprising a control unit for applying voltage to the foil.